Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/672,943	NUNEZ, CHRIS
Examiner	Art Unit
Yicun Wu	2165

	SEARCHED				
Class	Subclass	Date	Examiner		
707	1-10, 100- 104.1 200-206	6/6/2006	ΥW		
715,	515-517	6/6/2006	YW		
715	501	6/6/2006	YW		
711	137	6/6/2006	YW		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
inventor search (double patenting) uspto uspgpub epo jpo ibmtech derwent	6/6/2006	YW		
acm ieee citeseer internet Search stratagy attached	6/6/2006	YW		